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Example: optical <and> (fiber <or> fibre) <in> ti
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(condenser<paragraph>approach<paragraph>difference) <and> (fractional<paragraph>current)

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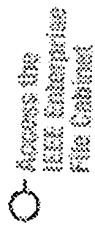
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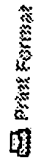
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```
(evaporator<paragraph>efficiency<paragraph>loss)<and>
(condenser<paragraph>efficiency<paragraph>loss)
```

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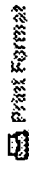
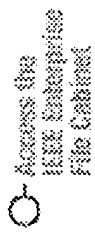
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